



<b>Title of Change:</b>	Update Typical Reading of Tr and Tf in Datasheet for 40V T6 products.		
<b>Effective date:</b>	15 May 2017		
<b>Contact information:</b>	Contact your local ON Semiconductor Sales Office or <guokun.yeng@onsemi.com>		
<b>Type of notification:</b>	ON Semiconductor will consider this change accepted.		
<b>Change category:</b>	<input type="checkbox"/> Wafer Fab Change <input type="checkbox"/> Assembly Change <input type="checkbox"/> Test Change <input checked="" type="checkbox"/> Other <u>Datasheet</u>		
<b>Change Sub-Category(s):</b>	<input type="checkbox"/> Manufacturing Site Change/Addition <input type="checkbox"/> Material Change <input checked="" type="checkbox"/> Datasheet/Product Doc change <input type="checkbox"/> Manufacturing Process Change <input type="checkbox"/> Product specific change <input type="checkbox"/> Shipping/Packaging/Marking <input type="checkbox"/> Other: _____		
<b>Sites Affected:</b>	<input type="checkbox"/> All site(s) <input type="checkbox"/> not applicable <input checked="" type="checkbox"/> ON Semiconductor site(s) : ON Seremban, Malaysia <input type="checkbox"/> External Foundry/Subcon site(s)		
<b>Description and Purpose:</b>			
<p>This Product Bulletin is announcing that ON Semiconductor is updating datasheet for below products. The change is to update typical reading of switching parameter, <b>Tr</b> and <b>Tf</b> to reflect the actual device performance. ON is improving the measurement method with reduce influence of parasitic inductance in the measurement PCB design.</p>			
<b>List of Affected Standard Parts:</b>			
NVMFS5C423NLAFT1G NVMFS5C423NLAFT3G NVMFS5C423NLT1G NVMFS5C423NLT3G NVMFS5C423NLWFAFT1G NVMFS5C423NLWFAFT3G NVMFS5C423NLWFT1G NVMFS5C423NLWFT3G NVMFS5C442NLAFT1G NVMFS5C442NLAFT3G NVMFS5C442NLT1G NVMFS5C442NLT3G NVMFS5C442NLWFAFT1G NVMFS5C442NLWFAFT3G NVMFS5C442NLWFT1G NVMFS5C442NLWFT3G NVMFS5C460NLAFT1G NVMFS5C460NLAFT3G NVMFS5C460NLT1G NVMFS5C460NLT3G NVMFS5C460NLWFAFT1G NVMFS5C460NLWFAFT3G NVMFS5C460NLWFT1G			